



CTL0502NS

N-Channel Enhancement MOSFET

Features

- Drain-Source Breakdown Voltage V_{DSS} 20 V
- Drain-Source On-Resistance
 $R_{DS(ON)}$ 21mΩ, at V_{GS} = 4.5V, I_D = 5.0A
 $R_{DS(ON)}$ 24mΩ, at V_{GS} = 2.5V, I_D = 3.5A
 $R_{DS(ON)}$ 31mΩ, at V_{GS} = 1.8V, I_D = 2.8A
- Continuous Drain Current at $T_c=25^\circ\text{C}$ I_D = 5.0A
- Advanced high cell density Trench Technology
- RoHS Compliance & Halogen Free

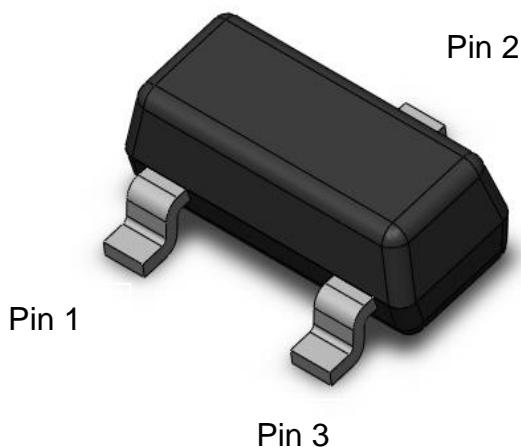
Description

The CTL0502NS uses high performance Trench Technology to provide excellent $R_{DS(ON)}$ and low gate charge which is suitable for most of the synchronous buck converter applications.

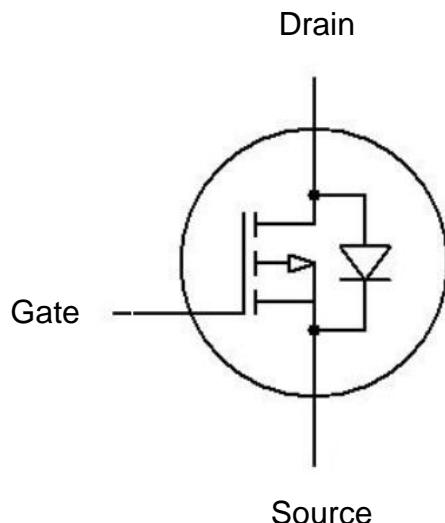
Applications

- Power Management
- Lithium Ion Battery

Package Outline



Schematic



Gate: Pin 1
Drain: Pin 2
Source: Pin 3



CTL0502NS

N-Channel Enhancement MOSFET

Absolute Maximum Rating at 25°C

Symbol	Parameters	Test Conditions	Min	Notes
V_{DS}	Drain-Source Voltage	20	V	
V_{GS}	Gate-Source Voltage	± 12	V	
I_D	Continuous Drain Current	5.0	A	1
I_{DM}	Pulsed Drain Current	25	A	1
P_D	Total Power Dissipation	1.4	W	2
T_{STG}	Storage Temperature Range	-55 to 150	°C	
T_J	Operating Junction Temperature Range	-55 to 150	°C	

Thermal Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$R_{\theta JA4}$	Thermal Resistance Junction-Ambient (t=10s)		--	175	--	°C /W	1,4



CTL0502NS

N-Channel Enhancement MOSFET

Electrical Characteristics $T_A = 25^\circ\text{C}$ (unless otherwise specified)

Static Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
B_{VDSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{V}$, $I_D = 250\mu\text{A}$	20	-	-	V	
I_{DSS}	Drain-Source Leakage Current	$V_{DS} = 20\text{V}$, $V_{GS} = 0\text{V}$	-	-	1	μA	
I_{GSS}	Gate-Source Leakage Current	$V_{GS} = \pm 12\text{V}$, $V_{DS} = 0\text{V}$	-	-	± 100	nA	

On Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$R_{DS(ON)}$	Drain-Source On-Resistance	$V_{GS} = 4.5\text{V}$, $I_D = 3.0\text{A}$	-	21	31	$\text{m}\Omega$	3
		$V_{GS} = 2.5\text{V}$, $I_D = 2.6\text{A}$	-	24	37	$\text{m}\Omega$	
		$V_{GS} = 1.8\text{V}$, $I_D = 1.0\text{A}$	-	31	47	$\text{m}\Omega$	
$V_{GS(th)}$	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = 250\mu\text{A}$	0.7	---	1.4	V	3

Dynamic Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
C_{iss}	Input Capacitance	$V_{GS} = 0\text{V}$, $V_{DS} = 10\text{V}$, $f = 1\text{MHz}$	-	668	-	pF	
C_{oss}	Output Capacitance		-	118	-		
C_{rss}	Reverse Transfer Capacitance		-	86	-		

Switching Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$T_{D(ON)}$	Turn-On Delay Time	$V_{DS} = 5\text{V}$, $V_{GS} = 4.5\text{V}$, $R_G = 6\Omega$, $I_D = 3.6\text{A}$	-	10.5	21	ns	
T_R	Rise Time		-	5	10		
$T_{D(OFF)}$	Turn-Off Delay Time		-	29.5	59		
T_F	Fall Time		-	4.5	9		
Q_G	Total Gate Charge	$V_{DS} = 10\text{V}$, $V_{GS} = 4.5\text{V}$, $I_D = 3.6\text{A}$	-	7.0	-	nC	
Q_{GS}	Gate-Source Charge		-	1.0	-		
Q_{GD}	Gate-Drain Charge		-	1.5	-		



CTL0502NS

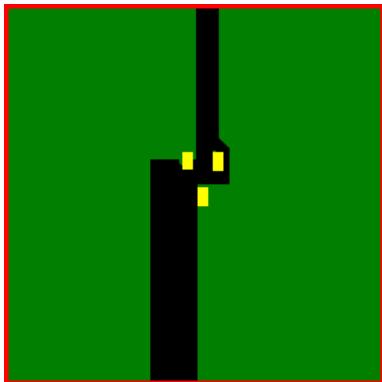
N-Channel Enhancement MOSFET

Drain-Source Diode Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
V _{SD}	Body Diode Forward Voltage	V _{GS} = 0V, I _D = 5.0	-	-	1.2	V	
I _{SD}	Body Diode Continuous Current		-	-	5.0	A	1

Note:

1. The power dissipation is limited by 150°C junction temperature.
2. Device mounted on a glass-epoxy board



Test Board

FR-4
25.4 x 25.4 mm .
2 Oz Copper

3. The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$
4. Thermal Resistance follow JESD51-3.



CTL0502NS

N-Channel Enhancement MOSFET

Typical Characteristic Curves

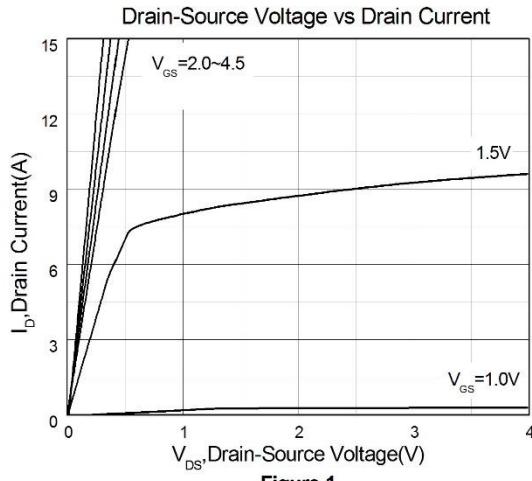


Figure 1

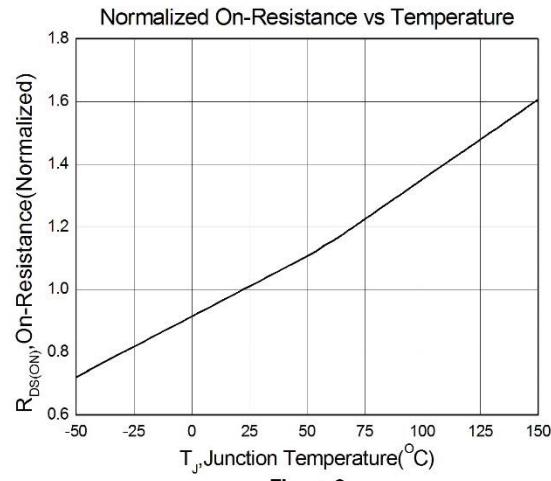


Figure 2

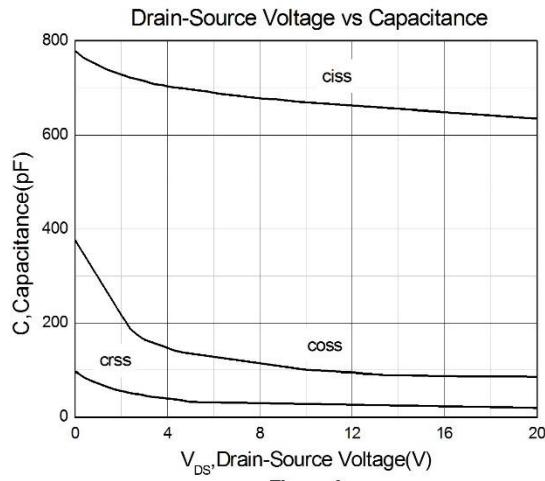


Figure 3

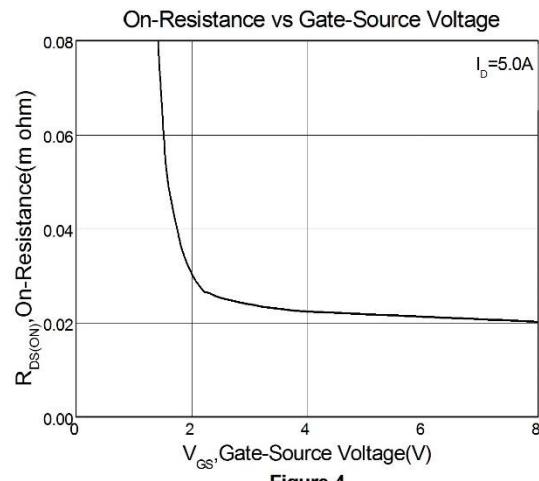


Figure 4

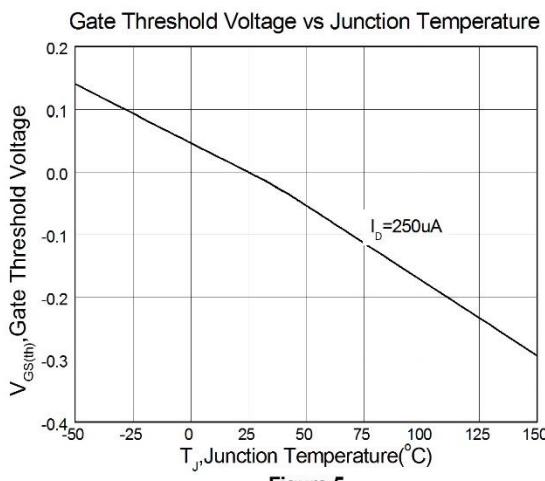


Figure 5

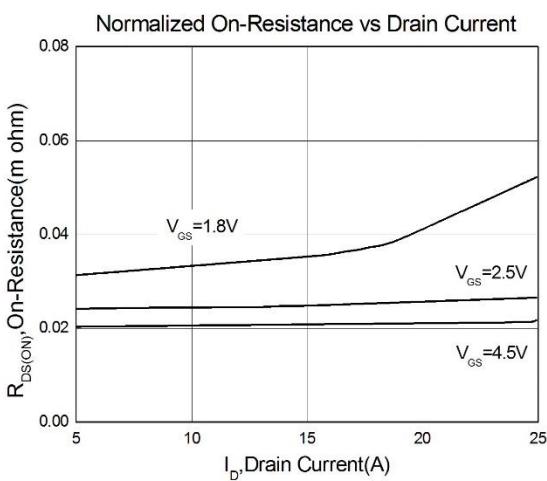


Figure 2



CTL0502NS

N-Channel Enhancement MOSFET

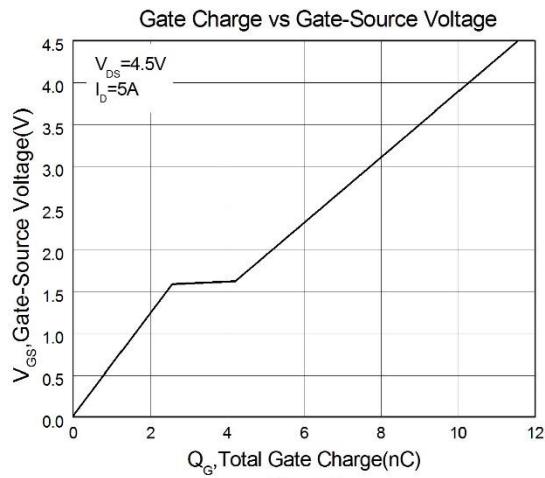


Figure 7

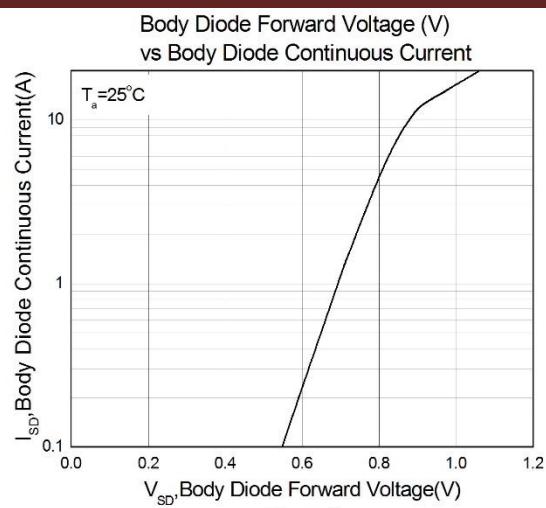


Figure 8



Test Circuits & Waveforms

Figure 9: Gate Charge Test Circuit

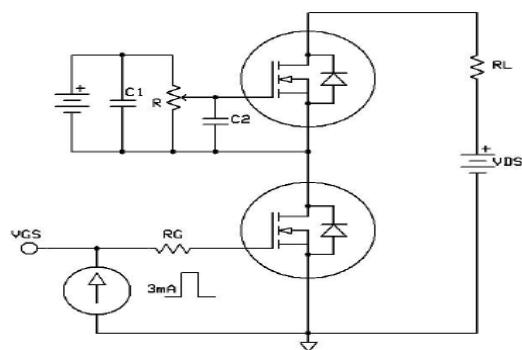


Figure 10: Gate Charge Waveform

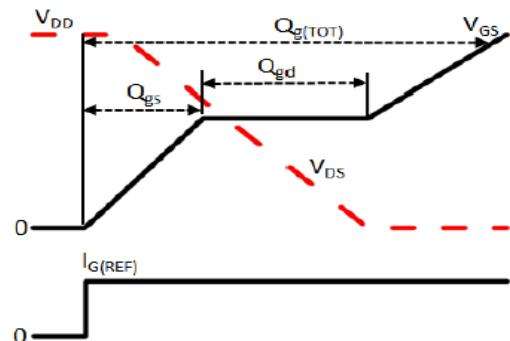


Figure 11: Switching Time Test Circuit

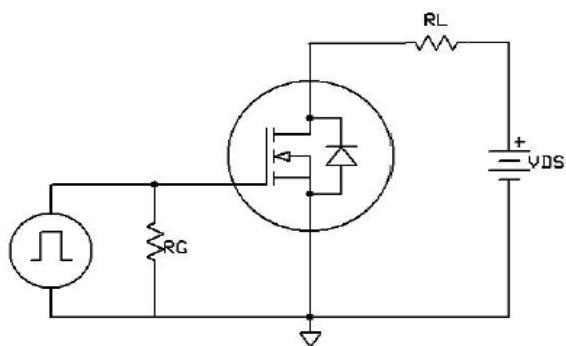
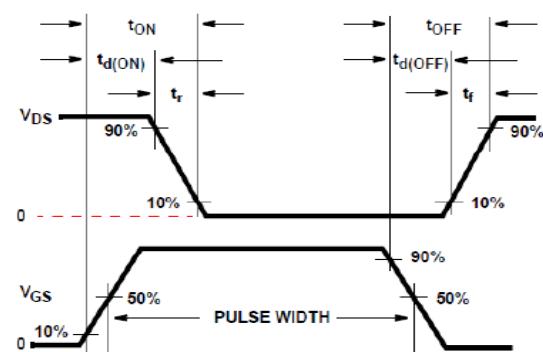


Figure 12: Switching Time Waveform

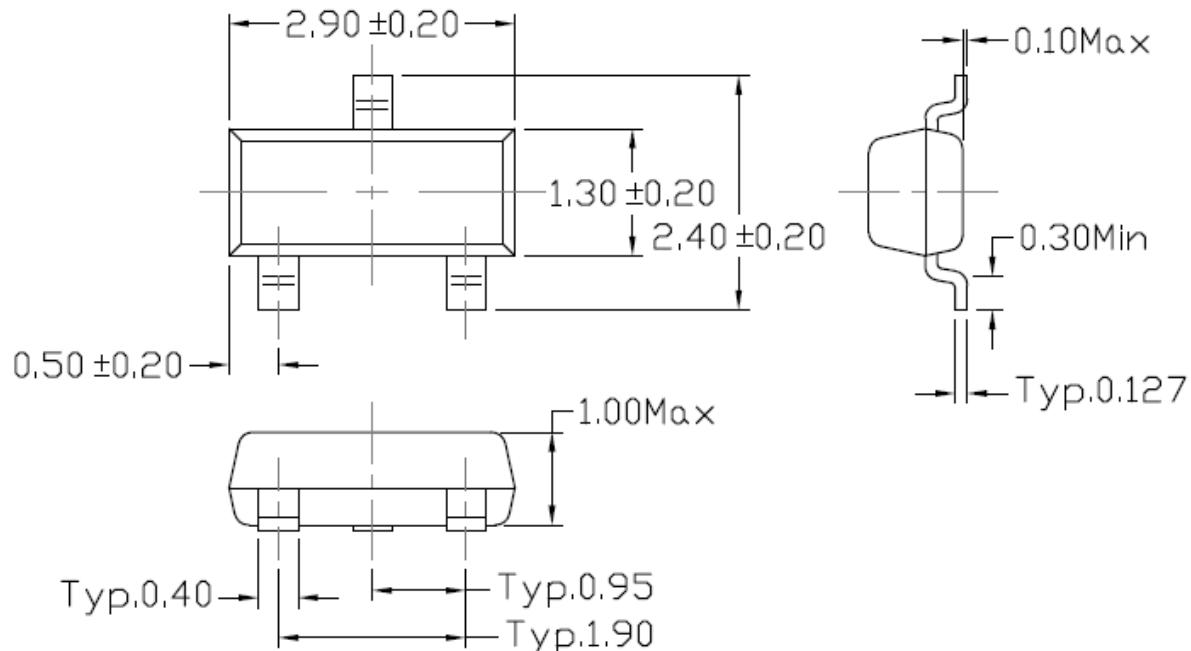




CTL0502NS

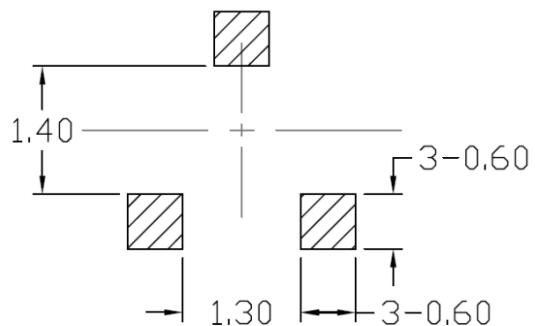
N-Channel Enhancement MOSFET

Package Dimension Dimensions in mm unless otherwise stated



Note: Dimensions in mm

Recommended pad layout for surface mount leadform



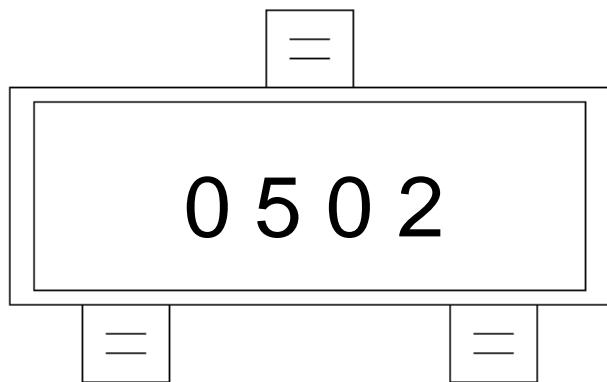
Note: Dimensions in mm



CTL0502NS

N-Channel Enhancement MOSFET

Marking Information



0502: Device Number

Ordering Information

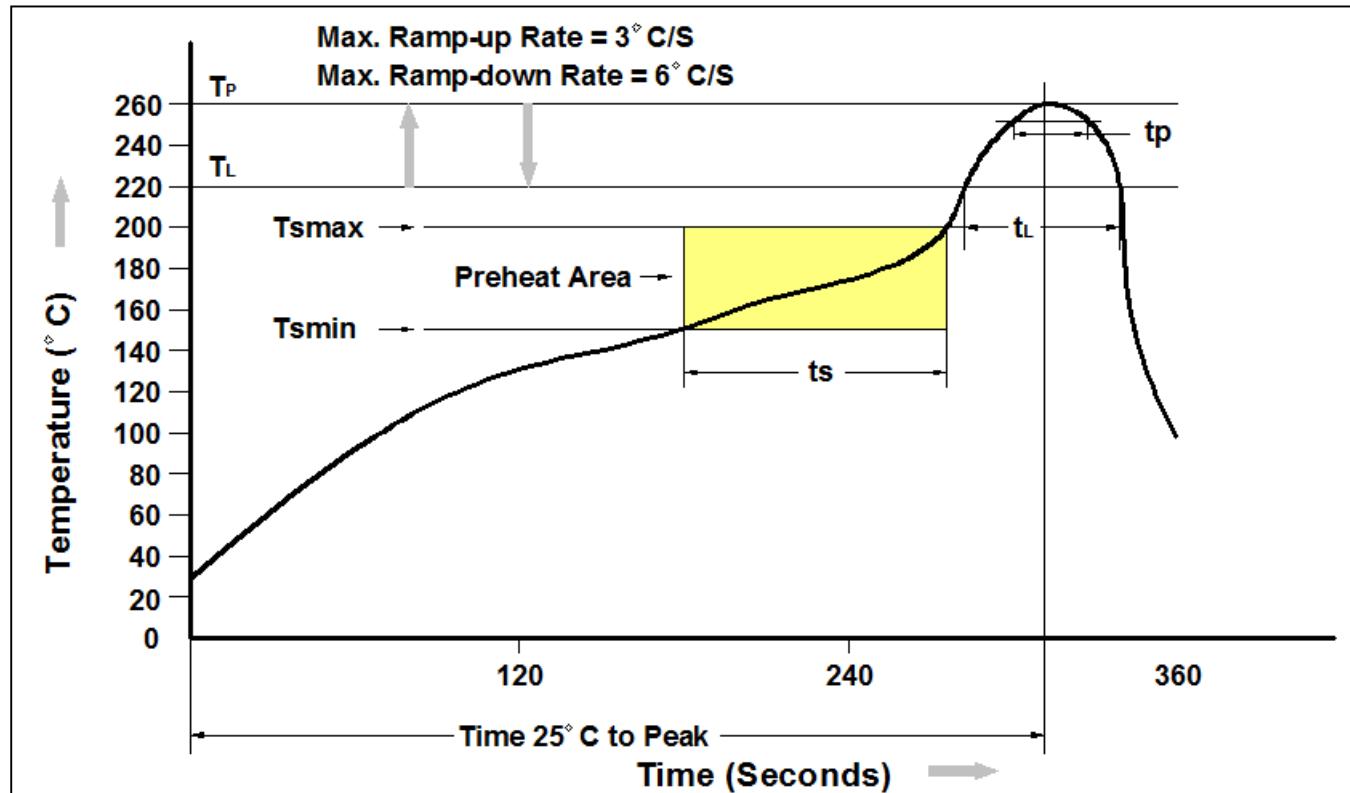
Part Number	Description	Quantity
CTL0502NS	SOT-23 Reel	3000 pcs



CTL0502NS

N-Channel Enhancement MOSFET

Reflow Profile



Profile Feature	Pb-Free Assembly Profile
Temperature Min. (Tsmin)	150°C
Temperature Max. (Tsmax)	200°C
Time (ts) from (Tsmin to Tsmax)	60-120 seconds
Ramp-up Rate (tL to tp)	3°C/second max.
Liquidous Temperature (TL)	217°C
Time (tL) Maintained Above (TL)	60 – 150 seconds
Peak Body Package Temperature	260°C +0°C / -5°C
Time (tp) within 5°C of 260°C	30 seconds
Ramp-down Rate (TP to TL)	6°C/second max
Time 25°C to Peak Temperature	8 minutes max.



CTL0502NS

N-Channel Enhancement MOSFET

DISCLAIMER

CT MICRO RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN. CT MICRO DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS.

CT MICRO ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT EXPRESS WRITTEN APPROVAL OF CT MICRO INTERNATIONAL CORPORATION.

1. *Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instruction for use provided in the labelling, can be reasonably expected to result in significant injury to the user.*
2. *A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.*